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## BIB DATA SHEET

CONFIRMATION NO. 8935

<b>SERIAL NUMBER</b> 10/553,470	<b>FILING or 371(c) DATE</b> 05/19/2006 <b>RULE</b>	<b>CLASS</b> 438	<b>GROUP ART UNIT</b> 2818	<b>ATTORNEY DOCKET NO.</b> 60291.000041		
<b>APPLICANTS</b> Ralf Lerner, Erfurt, GERMANY; <b>** CONTINUING DATA *****</b> This application is a 371 of PCT/DE04/00801 04/16/2004 <b>** FOREIGN APPLICATIONS *****</b> GERMANY 103 17 747.7 04/17/2003 <b>** IF REQUIRED, FOREIGN FILING LICENSE GRANTED **</b> 09/21/2006						
Foreign Priority claimed <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No 35 USC 119(a-d) conditions met <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No Verified and Acknowledged <u>/EARL N TAYLOR/</u> Examiner's Signature		<input type="checkbox"/> Met after Allowance ENT Initials	<b>STATE OR COUNTRY</b> GERMANY	<b>SHEETS DRAWINGS</b> 1	<b>TOTAL CLAIMS</b> 16	<b>INDEPENDENT CLAIMS</b> 2
<b>ADDRESS</b> HUNTON & WILLIAMS LLP INTELLECTUAL PROPERTY DEPARTMENT 1900 K STREET, N.W. SUITE 1200 WASHINGTON, DC 20006-1109 UNITED STATES						
<b>TITLE</b> Monitoring the reduction in thickness as material is removed from a wafer composite and test structure for monitoring removal of material						
<b>FILING FEE RECEIVED</b> 1690	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:			<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit		